

MOSFET Maximum Ratings T₁ = 25°C unless otherwise noted.

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-to-Source Voltage		-40	V
V _{GS}	Gate-to-Source Voltage		±20	V
-	Drain Current - Continuous (T _C < 90°C, V _{GS} =10)	(Note 1)	-32	
D	Pulsed Drain Current		See Figure 4	Α
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	121	mJ
-	Power Dissipation		83	W
PD	Derate Above 25°C		0.56	W/ºC
T _J , T _{STG}	Operating and Storage Temperature		-55 to + 175	°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.8	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient	(Note 3)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD4685	FDD4685-F085	D-PAK(TO-252)	13"	12mm	2500units

Notes:

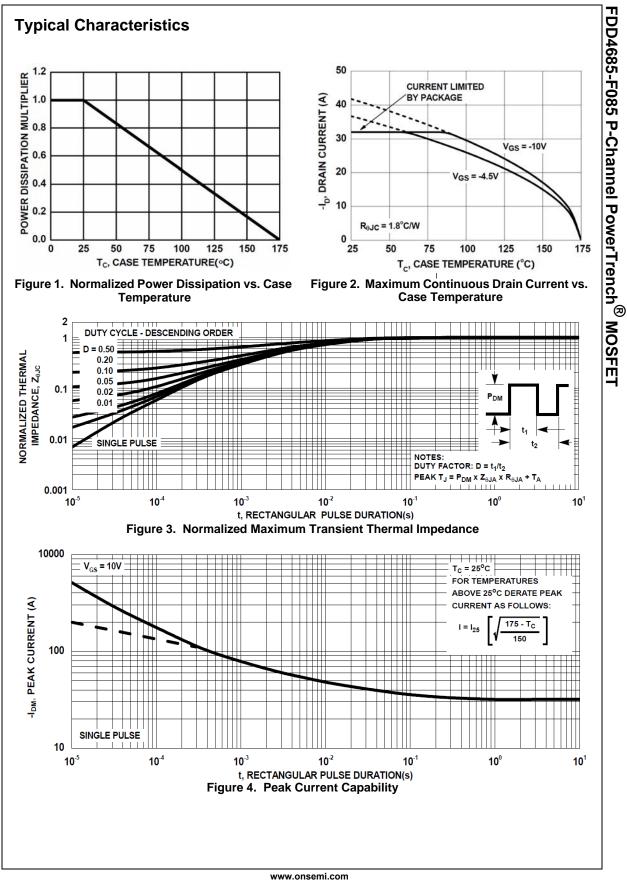
1. Current is limited by bondwire configuration.

2. Starting $T_J = 25^{\circ}$ C, L = 3mH, I_{AS} = 9A, V_{DD} = 40V during inductor charging and V_{DD} = 0V during time in avalanche. 3. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,JC}$ is guaranteed by design, while $R_{\theta,JA}$ is determined by the board design. The maximum rating

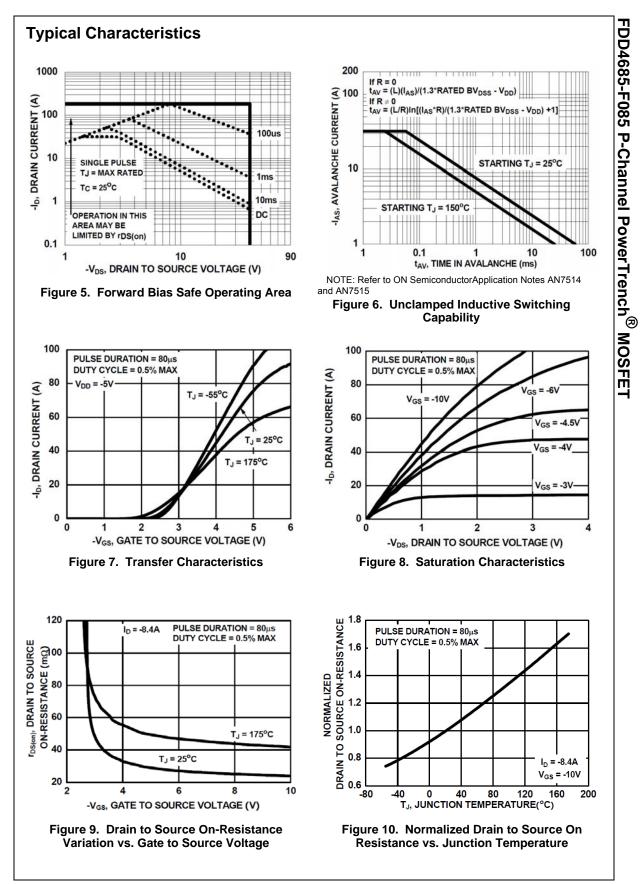
presented here is based on mounting on a 1 in² pad of 2oz copper.
4. A suffix as "...F085P" has been temporarily introduced in order to manage a double source strategy as ON Semiconductor has officially announced in Aug 2014.

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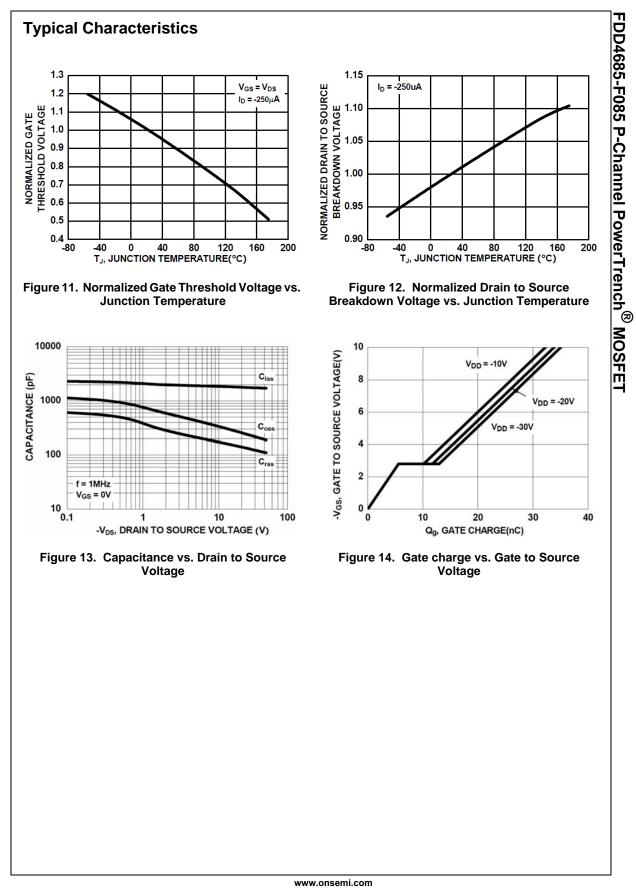
	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Cha	racteristics					
B _{VDSS}	Drain-to-Source Breakdown Voltage	I _D = -250μA, V _{GS} = 0V	-40	-	-	V
ΔB_{VDSS}	Breakdown Voltage Temperature	ID = -250μ A, referenced to 25° C	-	-33	-	mV/ºC
ΔTJ	Coefficient				1	
	Drain-to-Source Leakage Current	$V_{DS} = -32V$	-	-	-1	μΑ
I _{GSS} On Chai	Gate-to-Source Leakage Current	V _{GS} = ±20V	-	-	±100	nA
				10		
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1	-1.6	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	ID = -250μ A, referenced to 25° C	-	4.9	-	mV/ºC
		I _D = -8.4A, V _{GS} = -10V	-	23	27	
R _{DS(on)}	Drain to Source On Resistance	I _D = -7A, V _{GS} = -4.5V	-	30	35	mΩ
		I_D = -8.4A, V_{GS} = -10V, T_J = 150°C	-	38	45	
9 _{FS}	Forward Transconductance	ID = -8.4A, VDS = -5V	-	23	-	s
C _{iss} C _{oss}	Input Capacitance Output Capacitance	$-V_{DS} = -20V, V_{GS} = 0V,$	-	1790 260	2380 345	pF pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz	-	140	205	pF
R _g	Gate Resistance	f = 1MHz	-	4	-	Ω
Q _{g(ToT)}	Total Gate Charge		-	19	27	nC
Q _{gs}	Gate-to-Source Gate Charge	$-V_{DD} = -20V, V_{GS} = -5V,$	-	5.6	-	nC
Q _{gd}	Gate-to-Drain "Miller" Charge	I _D = -8.4A	-	6.1	-	nC
Switchii t _{d(on)}	ng Characteristics Turn-On Delay Rise Time	V _{DD} = -20V, I _D = -8.4A,	-	8 15	16 27	ns ns
t _{d(off)}	Turn-Off Delay	$V_{GS} = -10V, R_{GEN} = 6\Omega$	-	34	55	ns
t _f	Fall Time		_	14	26	ns
Drain-So V _{SD} t _{rr}	Source-to-Drain Diode Voltage Reverse-Recovery Time	I _{SD} = -8.4A, V _{GS} = 0V - I _{SD} = -8.4A, dI _{SD} /dt = 100A/μs	-	-0.85 30	-1.2 45	V ns
Q _{rr}	Reverse-Recovery Charge	SD = -0.47, $SD/01 = 10077$ µ3	-	31	47	nC



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